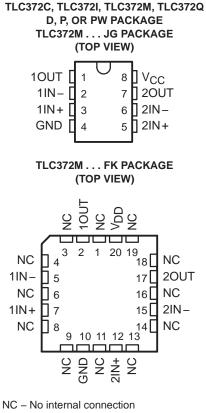
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- Single or Dual-Supply Operation
- Wide Range of Supply Voltages 2 V to 18 V
- Low Supply Current Drain
   150 μA Typ at 5 V
- Fast Response Time . . . 200 ns Typ for TTL-Level Input Step
- Built-in ESD Protection
- High Input Impedance . . .  $10^{12} \Omega$  Typ
- Extremely Low Input Bias Current 5 pA Typ
- Ultrastable Low Input Offset Voltage
- Input Offset Voltage Change at Worst-Case Input Conditions Typically 0.23 μV/Month, Including the First 30 Days
- Common-Mode Input Voltage Range Includes Ground
- Output Compatible With TTL, MOS, and CMOS
- Pin-Compatible With LM393

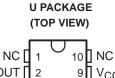
### description

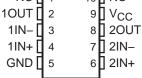
This device is fabricated using LinCMOS<sup>TM</sup> technology and consists of two independent voltage comparators, each designed to operate from a single power supply. Operation from dual supplies is also possible if the difference between the two supplies is 2 V to 18 V. Each device features extremely high input impedance (typically greater than  $10^{12} \Omega$ ), allowing direct interfacing with high-impedance sources. The outputs are n-channel open-drain configurations and can be connected to achieve positive-logic wired-AND relationships.

The TLC372 has internal electrostatic discharge (ESD) protection circuits and has been classified with a 1000-V ESD rating using human body model testing. However, care should be exercised in handling this device as exposure to ESD may result in a degradation of the device parametric performance.

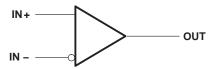








## symbol (each comparator)



The TLC372C is characterized for operation from 0°C to 70°C. The TLC372I is characterized for operation from -40°C to 85°C. The TLC372M is characterized for operation over the full military temperature range of -55°C to 125°C. The TLC372Q is characterized for operation from -40°C to 125°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

LinCMOS is a trademark of Texas Instruments Incorporated. All other trademarks are the property of their respective owners.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

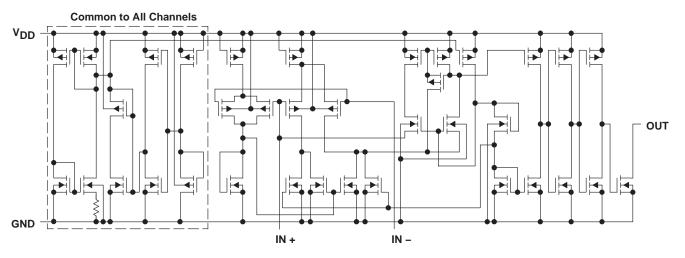


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# TLC372 LinCMOS™ DUAL DIFFERENTIAL COMPARATORS

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## equivalent schematic (each comparator)



#### AVAILABLE OPTIONS<sup>(1)</sup>

				PACKAGE	DEVICES		
TA	V <sub>IO</sub> max AT 25°C	SMALL OUTLINE (D) <sup>(2)</sup>	CHIP CARRIER (FK)	CERAMIC DIP (JG)	PLASTIC DIP (P)	TSSOP (PW)	CERAMIC FLAT PACK (U)
0°C to 70°C	5 mV	TLC372CD	—	—	TLC372CP	TLC372CPW	—
-40°C to 85°C	5 mV	TLC372ID	—	—	TLC372IP	_	—
–55°C to 125°C	5 mV	TLC372MD	TLC372MFK	TLC372MJG	TLC372MP	_	TLC372MU
-40°C to 125°C	5 mV	TLC372QD	—	—	TLC372QP		—

1. For the most current package and ordering information see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

2. The D packages are available taped and reeled. Add R suffix to device type (e.g., TLC372CDR).



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## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>DD</sub> (see Note 1)		
Differential input voltage, V <sub>ID</sub> (see Note 2)		
Input voltage range, V <sub>I</sub>	–0.3 V to 18	V
Output voltage, V <sub>O</sub>		V
Input current, I		
Output current, I <sub>O</sub>		
Duration of output short circuit to ground (see Note 3)	unlimite	ed
Package thermal impedance, $\theta_{JA}$ (see Notes 6 and 7)	: D package	Ν
	P package	Ν
	PW package 149°C/V	
Package thermal impedance, $\theta_{JC}$ (see Notes 6 and 7)		
	JG package 14.5°C/V	
	U package 14.7°C/V	Ν
Operating free-air temperature range, TA: TLC372C .		
TLC372I		С
TLC372M .		С
TLC372Q .		C
Storage temperature range		C
Case temperature for 60 seconds: FK package		
Lead temperature 1,6 mm (1/16 inch) from case for 10		
Lead temperature 1,6 mm (1/16 inch) from case for 60		

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 3. All voltage values except differential voltages are with respect to network ground.

- 4. Differential voltages are at IN+ with respect to IN -.
- 5. Short circuits from outputs to V<sub>DD</sub> can cause excessive heating and eventual device destruction.
- 6. Maximum power dissipation is a function of  $T_J(max)$ ,  $\theta_{JA}$ , and  $T_A$ . The maximum allowable power dissipation at any allowable ambient temperature is  $P_D = (T_J(max) T_A)/\theta_{JA}$ . Operating at the absolute maximum  $T_J$  of 150°C can affect reliability.
- 7. The package thermal impedance is calculated in accordance with JESD 51-7 (plastic) or MIL-STD-883 Method 1012 (ceramic).

## recommended operating conditions

		TLC3	72C	TLC	3721	TLC3	72M	TLC3	72Q	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Supply voltage, V <sub>DD</sub>		3	16	3	16	4	16	4	16	V
	V <sub>DD</sub> = 5 V	0	3.5	0	3.5	0	3.5	0	3.5	
Common-mode input voltage, VIC	V <sub>DD</sub> = 10 V	0	8.5	0	8.5	0	8.5	0	8.5	V
Operating free-air temperature, TA		0	70	-40	85	-55	125	-40	125	°C



Template Release Date: 7–11–94

# TLC372 LinCMOS™ DUAL DIFFERENTIAL COMPARATORS

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Itest condutions					+	TLC372C	172C	╞	TLC	TLC372I		TLC372M, TLC372Q	<u>и, тLC37</u>	2Q		
V(c)       Induct offset voltage       V(c) = V(c)(min. See Note4       Eatmange		PARAMETER	TEST	CONDITIONS	TAT			IAX	MIN		MAX	MIN		MAX	LIND	
Vio         Input offset current         Vio         Input offset current         Eul mage         Eul ma		2	2		25°C		-	5		-	S		-	5	14-1	
	0/2	Input offset voltage	VIC = VICRN		Full range			6.5			7			10	> E	
Induction         <					25°C		-			-			~		ЪА	
Ib         Induit bias current         Sec         5         6         5         6         6         5         7         5         7	<u>0</u>	Input offset current			MAX			0.3			-			10	hA	
Ib         Input blas current         Imput blas current <td></td> <td></td> <td></td> <td></td> <td>25°C</td> <td></td> <td>5</td> <td></td> <td></td> <td>5</td> <td></td> <td></td> <td>5</td> <td></td> <td>ЪА</td>					25°C		5			5			5		ЪА	
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	<u>8</u>	Input bias current			MAX			0.6			2			20	hA	
OLD         Value         OLD         Value         Va	.				25°C	0 to VDD-1			0 to /DD-1			0 to VDD-1			:	
Differ         High-level output current         VD = 1 V         VD = 5 V         25°C         0.1	/ICF				Full range	0 to VDD-1.5		>	0 to DD-1.5			0 to VDD-1.5			>	
OH         High-level output current         VID = 1V.         VOH = 15V         Full range         150         400         150			:	VOH = 5 V	25°C		0.1			0.1			0.1		hA	
QL         Low-level output voltage         VID = -1 V.         IOL = 4 mA         Z5°C         150         400         150	НО	High-level output cur	0 >	VOH = 15 V	Full range			-			-			ю	μA	
OL         Low-level output voltage         V(D = 1V, V)         OL = 4 mJ         Full range         Tool         Tool<	.				25°C			400		150	400		150	400	:	
OL         Low-level output current         V(D = -1V.         V(D = 15V         25°C         6         16         750         300         150         300         150         300         150         300         150         300         150         300         150         300         160         160         6         160         6         160     <	,oL			IOL = 4 mA	Full range			700			700			700	> E	
Db         Supply current (ivo comparators)         VID = 1 V, (ivo comparators)         Ivo comparators)	Ы	Low-level output curr	VID =	VOL = 1.5 V	25°C	9	16		9	16		9	16		шA	
DD         (wo comparators)         VID = 1.v,         wo rade         Full range         400         <		Supply current			25°C		150	300		150	300		150	300	<b>م</b> :	
All characteristics are measured with zero common-mode input voltage unless otherwise noted. Full range is 0°C to 7Tc372C, -40°C to 85°C for TLC372I, and -55°C ta 7Tc372M and -40°C to 125°C for TLC372L, IMPORTANT: See Parameter Measurement Information. TB : The offset voltage limits given are the maximum values required to drive the output above 4 V or below 400 mV with a 10-kD resistor between the output and VDD. They can be verified by applying the limit value to the input and checking for the appropriate output state. TE : The offset voltage limits given are the maximum values required to drive the output above 4 V or below 400 mV with a 10-kD resistor between the output and VDD. They can be verified by applying the limit value to the input and checking for the appropriate output state. Test constrained by applying the limit value to the input and checking for the appropriate output state. WICCHING CHARTECER, VDD = 5 V, TA = 25°C PARAMETER RL connected to 5 V through 5.1 kG, CL = 15 pF 1, 100-mV input step with 5-mV overdrive See Note 5 CL includes profe and jig capacitance.	DD	(two comparators)	vID = 1 v,		Full range			400			400			400	Yn.	
<b>5 V, T_A = 25°C</b> TEST CONDITIONS          MIN       TYP       MAX         TEST CONDITIONS       MIN       TYP       MAX         5 V through 5.1 kΩ, $C_L = 15 \text{ pF}^+$ , TL-level input step       100-mV input step       c50       c50         TTL-level input step       200       200       colspan="4">colspan="4">colspan="4">colspan="4">colspan="4">colspan="4">COL       COL       COL <td colspa="&lt;/th"><th>All c 125<sup>c</sup> DTE</th><th>haracteristics are measu °C for TLC372M and – 40 8: The offset voltage lir be verified by applyi</th><th>red with zero comm p°C to 125°C for TLK nits given are the m ing the limit value to</th><th>on-mode input volta 3372Q. IMPORTANT aximum values requir the input and checki</th><th>ge unless othen T. See Paramete red to drive the c ing for the appro</th><th>wise noted. Fu er Measuremer output above 4 opriate output s</th><th>II range i nt Informa V or belc state.</th><th>s 0°C tc ation. w 400 n</th><th>ר 70°C for 7 ר With a 1</th><th>-LC372( 0-kΩ res</th><th>C, -40°. sistor be</th><th>C to 85°C fo tween the o</th><th>or TLC37 output an</th><th>r2l, and d VDD.</th><th>l – 55°C t They car</th></td>	<th>All c 125<sup>c</sup> DTE</th> <th>haracteristics are measu °C for TLC372M and – 40 8: The offset voltage lir be verified by applyi</th> <th>red with zero comm p°C to 125°C for TLK nits given are the m ing the limit value to</th> <th>on-mode input volta 3372Q. IMPORTANT aximum values requir the input and checki</th> <th>ge unless othen T. See Paramete red to drive the c ing for the appro</th> <th>wise noted. Fu er Measuremer output above 4 opriate output s</th> <th>II range i nt Informa V or belc state.</th> <th>s 0°C tc ation. w 400 n</th> <th>ר 70°C for 7 ר With a 1</th> <th>-LC372( 0-kΩ res</th> <th>C, -40°. sistor be</th> <th>C to 85°C fo tween the o</th> <th>or TLC37 output an</th> <th>r2l, and d VDD.</th> <th>l – 55°C t They car</th>	All c 125 <sup>c</sup> DTE	haracteristics are measu °C for TLC372M and – 40 8: The offset voltage lir be verified by applyi	red with zero comm p°C to 125°C for TLK nits given are the m ing the limit value to	on-mode input volta 3372Q. IMPORTANT aximum values requir the input and checki	ge unless othen T. See Paramete red to drive the c ing for the appro	wise noted. Fu er Measuremer output above 4 opriate output s	II range i nt Informa V or belc state.	s 0°C tc ation. w 400 n	ר 70°C for 7 ר With a 1	-LC372( 0-kΩ res	C, -40°. sistor be	C to 85°C fo tween the o	or TLC37 output an	r2l, and d VDD.	l – 55°C t They car
TEST CONDITIONS       MIN       TYP       MAX         acted to 5 V through 5.1 kΩ, $C_L = 15 \text{ pF} \ddagger$ , $100\text{-mV}$ input step with 5-mV overdrive       650       650       650       200	wit	ching characteris	stics, V <sub>DD</sub> = 5	: V, T <sub>A</sub> = 25°C												
ected to 5 V through 5.1 k.g., $C_L = 15 pF \ddagger$ ,       100-mV input step with 5-mV overdrive       650         3 5       TTL-level input step       200         3 6       the interval between the input step function and the instant when the output crosses 1.4 V.       200		PARAMETER			TEST CO	NDITIONS						MIN	ТΥР	MAX	UNIT	
TTL-level input step 200 200 sthe interval between the input step function and the instant when the output crosses 1.4 V.			RI connected to 5	rough 5.1 kΩ,	= 15 pF‡,	100-mV input s	step with	5-mV o	verdrive				650		ŝ	
CL includes probe and jig capacitance. OTE 9: The response time specified is the interval between the input step function and the instant when the output crosses 1.4 V.	fsar		See Note 5	)		TTL-level input	step						200		2	
	IOTE JOTE	ncludes probe and jig cal E 9: The response time time time time time time time tim	pacitance. specified is the inter	val between the inpu	ut step function é	and the instant	when th	e outpui	t crosses 1	4.						



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electrical characteristics at specified free-air temperature, V <sub>DD</sub> = 5 V, T <sub>A</sub> = 25°C (unless otherwise	è
noted)	

				TL	.C372Y		
	PARAMETER	TEST CON	DITIONS	MIN	TYP	MAX	UNIT
VIO	Input offset voltage	$V_{IC} = V_{ICR}min$ ,	See Note 4		1	5	mV
IIO	Input offset current				1		pА
I <sub>IB</sub>	Input bias current				5		pА
VICR	Common-mode input voltage range			0 to V <sub>DD</sub> -1			V
IOH	High-level output current	V <sub>ID</sub> = 1 V,	V <sub>OH</sub> = 5 V		0.1		nA
VOL	Low-level output voltage	$V_{ID} = -1 V$ ,	$I_{OL} = 4 \text{ mA}$		150	400	mV
IOL	Low-level output current	$V_{ID} = -1 V$ ,	V <sub>OL</sub> = 1.5 V	6	16		mA
IDD	Supply current (two comparators)	V <sub>ID</sub> = 1 V,	No load		150	300	μΑ

<sup>†</sup> All characteristics are measured with zero common-mode input voltage unless otherwise noted. IMPORTANT: See Parameter Measurement Information.

NOTE 4: The offset voltage limits given are the maximum values required to drive the output above 4 V or below 400 mV with a 10-kΩ resistor between the output and V<sub>DD</sub>. They can be verified by applying the limit value to the input and checking for the appropriate output state.

## PARAMETER MEASUREMENT INFORMATION

The digital output stage of the TLC372 can be damaged if it is held in the linear region of the transfer curve. Conventional operational amplifier/comparator testing incorporates the use of a servo loop that is designed to force the device output to a level within this linear region. Since the servo-loop method of testing cannot be used, the following alternatives for measuring parameters such as input offset voltage, common-mode rejection, etc., are offered.

To verify that the input offset voltage falls within the limits specified, the limit value is applied to the input as shown in Figure 1(a). With the noninverting input positive with respect to the inverting input, the output should be high. With the input polarity reversed, the output should be low.

A similar test can be made to verify the input offset voltage at the common-mode extremes. The supply voltages can be slewed as shown in Figure 1(b) for the V<sub>ICR</sub> test, rather than changing the input voltages, to provide greater accuracy.

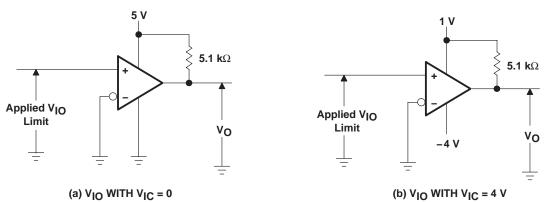


Figure 1. Method for Verifying That Input Offset Voltage is Within Specified Limits



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## PARAMETER MEASUREMENT INFORMATION

A close approximation of the input offset voltage can be obtained by using a binary search method to vary the differential input voltage while monitoring the output state. When the applied input voltage differential is equal, but opposite in polarity, to the input offset voltage, the output changes states.

Figure 2 illustrates a practical circuit for direct dc measurement of input offset voltage that does not bias the comparator into the linear region. The circuit consists of a switching-mode servo loop in which U1a generates a triangular waveform of approximately 20-mV amplitude. U1b acts as a buffer, with C2 and R4 removing any residual dc offset. The signal is then applied to the inverting input of the comparator under test, while the noninverting input is driven by the output of the integrator formed by U1c through the voltage divider formed by R9 and R10. The loop reaches a stable operating point when the output of the comparator under test has a duty cycle of exactly 50%, which can only occur when the incoming triangle wave is sliced symmetrically or when the voltage at the noninverting input exactly equals the input offset voltage.

Voltage divider R9 and R10 provides a step up of the input offset voltage by a factor of 100 to make measurement easier. The values of R5, R8, R9, and R10 can significantly influence the accuracy of the reading; therefore, it is suggested that their tolerance level be 1% or lower.

Measuring the extremely low values of input current requires isolation from all other sources of leakage current and compensation for the leakage of the test socket and board. With a good picoammeter, the socket and board leakage can be measured with no device in the socket. Subsequently, this open-socket leakage value can be subtracted from the measurement obtained with a device in the socket to obtain the actual input current of the device.

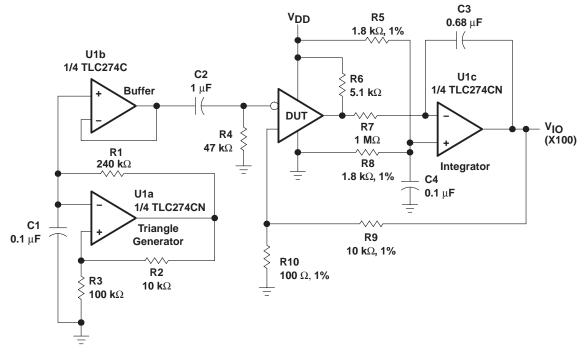


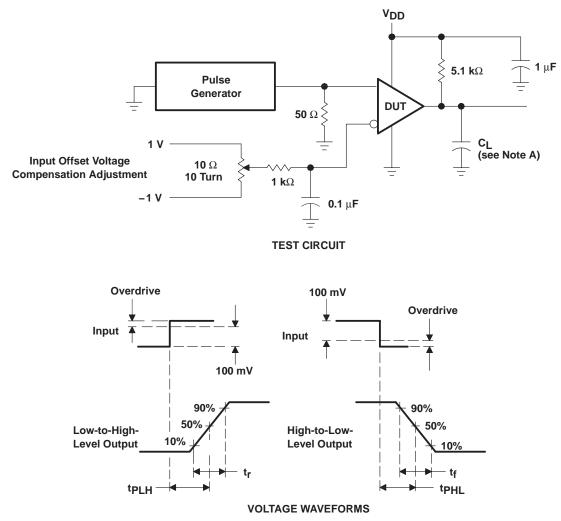
Figure 2. Circuit for Input Offset Voltage Measurement



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## PARAMETER MEASUREMENT INFORMATION

Response time is defined as the interval between the application of an input step function and the instant when the output reaches 50% of its maximum value. Response time, low-to-high level output, is measured from the leading edge of the input pulse, while response time, high-to-low level output, is measured from the trailing edge of the input pulse. Response-time measurement at low input signal levels can be greatly affected by the input offset voltage. The offset voltage should be balanced by the adjustment at the inverting input as shown in Figure 3, so that the circuit is just at the transition point. Then a low signal, for example 105-mV or 5-mV overdrive, causes the output to change state.









# TLC372 LinCMOS™ DUAL DIFFERENTIAL COMPARATORS

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## PRINCIPLES OF OPERATION

## LinCMOS<sup>™</sup> process

The LinCMOS<sup>™</sup> process is a Linear polysilicon-gate complementary-MOS process. Primarily designed for single-supply applications, LinCMOS<sup>™</sup> products facilitate the design of a wide range of high-performance analog functions, from operational amplifiers to complex mixed-mode converters.

While digital designers are experienced with CMOS, MOS technologies are relatively new for analog designers. This short guide is intended to answer the most frequently asked questions related to the quality and reliability of LinCMOS<sup>™</sup> products. Further questions should be directed to the nearest Texas Instruments field sales office.

### electrostatic discharge

CMOS circuits are prone to gate oxide breakdown when exposed to high voltages even if the exposure is only for very short periods of time. Electrostatic discharge (ESD) is one of the most common causes of damage to CMOS devices. It can occur when a device is handled without proper consideration for environmental electrostatic charges, e.g. during board assembly. If a circuit in which one amplifier from a dual operational amplifier is being used and the unused pins are left open, high voltages tends to develop. If there is no provision for ESD protection, these voltages may eventually punch through the gate oxide and cause the device to fail. To prevent voltage buildup, each pin is protected by internal circuitry.

Standard ESD-protection circuits safely shunt the ESD current by providing a mechanism whereby one or more transistors break down at voltages higher than the normal operating voltages but lower than the breakdown voltage of the input gate. This type of protection scheme is limited by leakage currents which flow through the shunting transistors during normal operation after an ESD voltage has occurred. Although these currents are small, on the order of tens of nanoamps, CMOS amplifiers are often specified to draw input currents as low as tens of picoamps.

To overcome this limitation, Texas Instruments design engineers developed the patented ESD-protection circuit shown in Figure 4. This circuit can withstand several successive 1-kV ESD pulses, while reducing or eliminating leakage currents that may be drawn through the input pins. A more detailed discussion of the operation of Texas Instruments's ESD- protection circuit is presented on the next page.

All input and output pins on LinCMOS and Advanced LinCMOS<sup>™</sup> products have associated ESD-protection circuitry that undergoes qualification testing to withstand 1000 V discharged from a 100-pF capacitor through a 1500-Ω resistor (human body model) and 200 V from a 100-pF capacitor with no current-limiting resistor (charged device model). These tests simulate both operator and machine handling of devices during normal test and assembly operations.

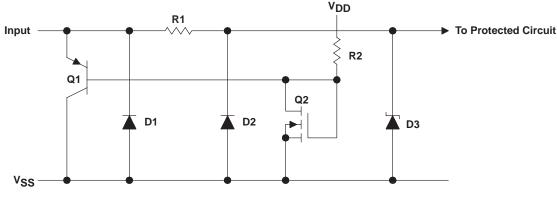


Figure 4. LinCMOS™ ESD-Protection Schematic

Advanced LinCMOS is a trademark of Texas Instruments Incorporated.



## **PRINCIPLES OF OPERATION**

### input protection circuit operation

Texas Instruments' patented protection circuitry allows for both positive-and negative-going ESD transients. These transients are characterized by extremely fast rise times and usually low energies, and can occur both when the device has all pins open and when it is installed in a circuit.

### positive ESD transients

Initial positive charged energy is shunted through Q1 to V<sub>SS</sub>. Q1 turns on when the voltage at the input rises above the voltage on the V<sub>DD</sub> pin by a value equal to the V<sub>EB</sub> of Q1. The base current increases through R2 with input current as Q1 saturates. The base current through R2 forces the voltage at the drain and gate of Q2 to exceed its threshold level (V<sub>T</sub> ~ 22 V to 26 V) and turn Q2 on. The shunted input current through Q1 to V<sub>SS</sub> is now shunted through the n-channel enhancement-type MOSFET Q2 to V<sub>SS</sub>. If the voltage on the input pin continues to rise, the breakdown voltage of the zener diode D3 is exceeded, and all remaining energy is dissipated in R1 and D3. The breakdown voltage of D3 is designed to be 24 V to 27 V, which is well below the gate oxide voltage of the circuit to be protected.

### negative ESD transients

The negative charged ESD transients are shunted directly through D1. Additional energy is dissipated in R1 and D2 as D2 becomes forward biased. The voltage seen by the protected circuit is -0.3 V to -1 V (the forward voltage of D1 and D2).

#### circuit-design considerations

LinCMOS<sup>™</sup> products are being used in actual circuit environments that have input voltages that exceed the recommended common-mode input voltage range and activate the input protection circuit. Even under normal operation, these conditions occur during circuit power up or power down, and in many cases, when the device is being used for a signal conditioning function. The input voltages can exceed V<sub>ICR</sub> and not damage the device only if the inputs are current limited. The recommended current limit shown on most product data sheets is ±5 mA. Figure 5 and Figure 6 show typical characteristics for input voltage versus input current.

Normal operation and correct output state can be expected even when the input voltage exceeds the positive supply voltage. Again, the input current should be externally limited even though internal positive current limiting is achieved in the input protection circuit by the action of Q1. When Q1 is on, it saturates and limits the current to approximately 5-mA collector current by design. When saturated, Q1 base current increases with input current. This base current is forced into the V<sub>DD</sub> pin and into the device I<sub>DD</sub> or the V<sub>DD</sub> supply through R2 producing the current limiting effects shown in Figure 5. This internal limiting lasts only as long as the input voltage is below the V<sub>T</sub> of Q2.

When the input voltage exceeds the negative supply voltage, normal operation is affected and output voltage states may not be correct. Also, the isolation between channels of multiple devices (duals and quads) can be severely affected. External current limiting must be used since this current is directly shunted by D1 and D2 and no internal limiting is achieved. If normal output voltage states are required, an external input voltage clamp is required (see Figure 7).

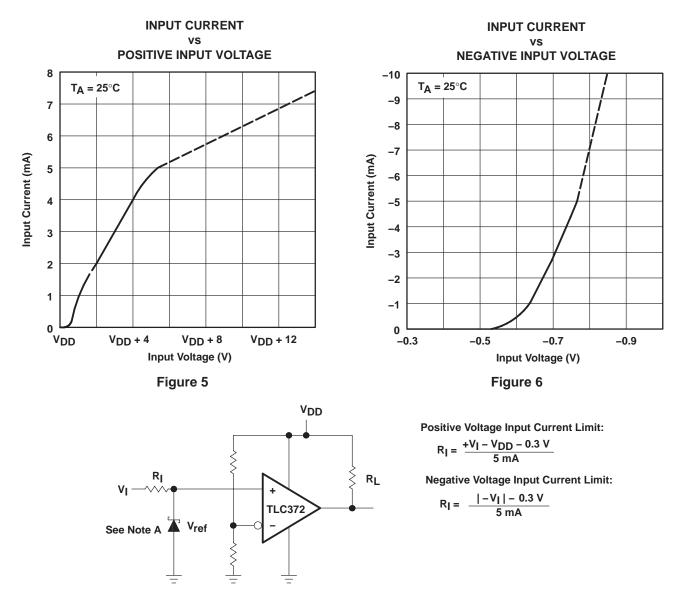


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## PRINCIPLES OF OPERATION

## circuit-design considerations (continued)



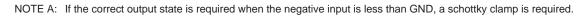


Figure 7. Typical Input Current-Limiting Configuration for a LinCMOS™ Comparator





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## **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
5962-87658012A	ACTIVE	LCCC	FK	20	1	TBD	Call TI	Call TI	
5962-8765801PA	ACTIVE	CDIP	JG	8	1	TBD	Call TI	Call TI	
5962-9554901NXD	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
5962-9554901NXDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CP	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
TLC372CPE4	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
TLC372CPSR	ACTIVE	SO	PS	8	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CPSRG4	ACTIVE	SO	PS	8	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CPW	ACTIVE	TSSOP	PW	8	150	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CPWG4	ACTIVE	TSSOP	PW	8	150	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CPWLE	OBSOLETE	TSSOP	PW	8		TBD	Call TI	Call TI	
TLC372CPWR	ACTIVE	TSSOP	PW	8	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372CPWRG4	ACTIVE	TSSOP	PW	8	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372ID	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372IDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	



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Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	Eco Plan <sup>(2)</sup>	Lead/ Ball Finish	MSL Peak Temp <sup>(3)</sup>	Samples (Requires Login)
TLC372IDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372IDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372IP	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
TLC372IPE4	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
TLC372MD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372MDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372MDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372MDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372MFKB	ACTIVE	LCCC	FK	20	1	TBD	POST-PLATE	N / A for Pkg Type	
TLC372MJG	ACTIVE	CDIP	JG	8	1	TBD	A42	N / A for Pkg Type	
TLC372MJGB	ACTIVE	CDIP	JG	8	1	TBD	A42	N / A for Pkg Type	
TLC372MP	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	
TLC372MUB	ACTIVE	CFP	U	10	1	TBD	A42	N / A for Pkg Type	
TLC372QD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372QDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372QDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	
TLC372QDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

# PACKAGE OPTION ADDENDUM



27-Apr-2012

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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#### OTHER QUALIFIED VERSIONS OF TLC372, TLC372M :

Catalog: TLC372

• Enhanced Product: TLC372-EP, TLC372-EP

• Military: TLC372M

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications

# PACKAGE MATERIALS INFORMATION

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## TAPE AND REEL INFORMATION

### REEL DIMENSIONS

TEXAS INSTRUMENTS





#### TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

# TAPE AND REEL INFORMATION

\*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
5962-9554901NXDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLC372CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLC372CPSR	SO	PS	8	2000	330.0	16.4	8.2	6.6	2.5	12.0	16.0	Q1
TLC372CPWR	TSSOP	PW	8	2000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1
TLC372IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLC372MDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLC372QDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

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# PACKAGE MATERIALS INFORMATION

14-Jul-2012



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
5962-9554901NXDR	SOIC	D	8	2500	367.0	367.0	35.0
TLC372CDR	SOIC	D	8	2500	340.5	338.1	20.6
TLC372CPSR	SO	PS	8	2000	367.0	367.0	38.0
TLC372CPWR	TSSOP	PW	8	2000	367.0	367.0	35.0
TLC372IDR	SOIC	D	8	2500	340.5	338.1	20.6
TLC372MDR	SOIC	D	8	2500	367.0	367.0	35.0
TLC372QDR	SOIC	D	8	2500	367.0	367.0	35.0

# **MECHANICAL DATA**

MCER001A - JANUARY 1995 - REVISED JANUARY 1997



### **CERAMIC DUAL-IN-LINE**



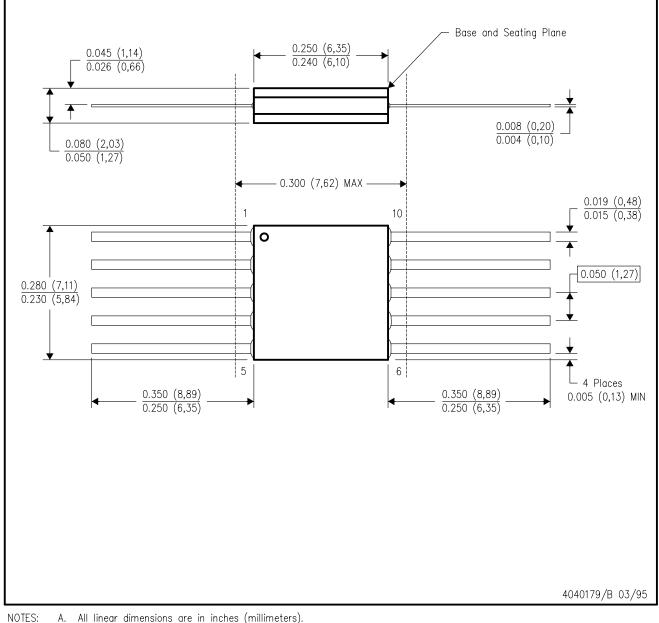
NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification.
- E. Falls within MIL STD 1835 GDIP1-T8



U (S-GDFP-F10)

CERAMIC DUAL FLATPACK



- Α. All linear dimensions are in inches (millimeters).
  - This drawing is subject to change without notice. Β.
  - This package can be hermetically sealed with a ceramic lid using glass frit. C.
  - D. Index point is provided on cap for terminal identification only.
  - E. Falls within MIL STD 1835 GDFP1-F10 and JEDEC MO-092AA



LEADLESS CERAMIC CHIP CARRIER

FK (S-CQCC-N\*\*) 28 TERMINAL SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

- C. This package can be hermetically sealed with a metal lid.
- D. Falls within JEDEC MS-004



P(R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
   E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



## **MECHANICAL DATA**

# PS (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.





NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
   E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G8)

PLASTIC SMALL OUTLINE



Α. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. Ŗ. This drawing is subject to change without notice.

🖄 Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153



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